



FORM HDP-1449 (Based on Form PTO-1449)

**PATENT AND TRADEMARK OFFICE**  
**INFORMATION DISCLOSURE CITATION**  
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Sheet 1 of 1

ATTORNEY DOCKET No.

9319S-000213

SERIAL No.

09/865,186

APPLICANT

Manabu Hanakawa

FILING DATE

May 24, 2001

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Ref. Desig.	Examiner's Initials	Document Number	Date	Name	Class/ Subclass	(If appropriate) Filing Date
1.	P	6,219,124	Apr/2001	Lee, et al.	/	

**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	P	10-0188110 /	June/1999	Korea	/		X
2.	Q	9-26589 /	Jan/1997	Japan	/	Abstract	

**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

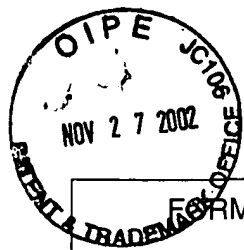
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1.		<del>Korean Examination Result</del>

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**FOREIGN PATENT DOCUMENTS**

Ref. Desig.	Examiner's Initials	Document Number	Date	Country	Class/ Subclass	Translation Yes	No
1.	Q	09-152623 /	6/10/1997	Japan		Abstract	
2.	Q	06-222372 /	8/12/1994	Japan		X	
3.	Q	04-037146 /	2/7/1992	Japan		X	
4.	Q	02-245735 /	10/1/1990	Japan		X	
5.	Q	03-144421 /	6/19/1991	Japan		X	
6.	Q	04-166916 /	6/12/1992	Japan		X	
7.	Q	04-217229 /	8/7/1992	Japan		X	
8.	Q	05-224225 /	9/3/1993	Japan		X	
9.	Q	06-289413 /	10/18/1994	Japan		X	
10.	Q	JP03-29830U /	1991	Japan		X	

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**OTHER DOCUMENTS (including Author, Title, Date, Pertinent Pages, etc.)**

Ref. Desig.	Examiner's Initials	
1.		<del>Examination results of corresponding Japanese Application No. 2001-103495</del>

Examiner:

Date Considered: 5/17/02

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